### **Power MOSFET**

## 60 V, 4.0 m $\Omega$ , 100 A, Single N-Channel

#### **Features**

- Small Footprint (5x6 mm) for Compact Design
- Low R<sub>DS(on)</sub> to Minimize Conduction Losses
- Low Q<sub>G</sub> and Capacitance to Minimize Driver Losses
- NVMFS5C645NLWF Wettable Flank Option for Enhanced Optical Inspection
- AEC-Q101 Qualified and PPAP Capable
- These Devices are Pb-Free and are RoHS Compliant

#### MAXIMUM RATINGS (T<sub>J</sub> = 25°C unless otherwise noted)

Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			$V_{DSS}$	60	V
Gate-to-Source Voltage	Э		V <sub>GS</sub>	±20	V
Continuous Drain	Steady	T <sub>C</sub> = 25°C	I <sub>D</sub>	100	Α
Current $R_{\theta JC}$ (Notes 1, 3)		T <sub>C</sub> = 100°C		71	
Power Dissipation	State	T <sub>C</sub> = 25°C	$P_{D}$	79	W
R <sub>θJC</sub> (Note 1)		T <sub>C</sub> = 100°C		40	
Continuous Drain	Steady	T <sub>A</sub> = 25°C	I <sub>D</sub>	22	Α
Current R <sub>0JA</sub> (Notes 1, 2, 3)		T <sub>A</sub> = 100°C		15	
Power Dissipation	State	T <sub>A</sub> = 25°C	$P_{D}$	3.7	W
R <sub>θJA</sub> (Notes 1 & 2)		T <sub>A</sub> = 100°C		1.8	
Pulsed Drain Current	$T_A = 25^{\circ}C$ , $t_p = 10 \mu s$		I <sub>DM</sub>	820	Α
Operating Junction and Storage Temperature			T <sub>J</sub> , T <sub>stg</sub>	-55 to +175	°C
Source Current (Body Diode)			Is	100	Α
Single Pulse Drain-to-Source Avalanche Energy (I <sub>L(pk)</sub> = 5 A)			E <sub>AS</sub>	185	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			T <sub>L</sub>	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

#### THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case - Steady State	$R_{ heta JC}$	1.9	°C/W
Junction-to-Ambient - Steady State (Note 2)	$R_{\theta JA}$	41	

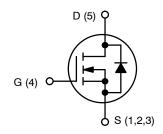
- The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
- 2. Surface-mounted on FR4 board using a 650 mm<sup>2</sup>, 2 oz. Cu pad.
- Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.



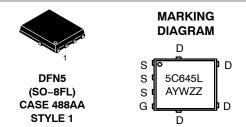
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V <sub>(BR)DSS</sub>	R <sub>DS(ON)</sub> MAX	I <sub>D</sub> MAX	
60 V	4.0 mΩ @ 10 V	100 1	
	5.7 mΩ @ 4.5 V	100 A	



**N-CHANNEL MOSFET** 



5C645L = Specific Device Code A = Assembly Location

Y = Year
W = Work Week
ZZ = Lot Traceability

### **ORDERING INFORMATION**

See detailed ordering, marking and shipping information in the package dimensions section on page 5 of this data sheet.

### **ELECTRICAL CHARACTERISTICS** ( $T_J = 25^{\circ}C$ unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit	
OFF CHARACTERISTICS								
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		60			V	
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> /				15.5		mV/°C	
Zero Gate Voltage Drain Current	voltage Drain Current $I_{DSS}$ $V_{GS} = 0 \text{ V}$ , $T_{J} = 25 \text{ °C}$		T <sub>J</sub> = 25 °C			10		
		V <sub>DS</sub> = 48 V	T <sub>J</sub> = 125°C			250	μΑ	
Gate-to-Source Leakage Current	I <sub>GSS</sub>	V <sub>DS</sub> = 0 V, V <sub>GS</sub> = 20 V				100	nA	
ON CHARACTERISTICS (Note 4)								
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}, I_{D}$	= 250 μΑ	1.2		2.0	V	
Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>				-4.9		mV/°C	
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 50 A		3.3	4.0		
		V <sub>GS</sub> = 4.5 V	I <sub>D</sub> = 50 A		4.6	5.7	mΩ	
Forward Transconductance	9 <sub>FS</sub>	V <sub>DS</sub> = 15 V, I	<sub>D</sub> = 50 A		105		S	
CHARGES, CAPACITANCES & GATE RE	SISTANCE						-	
Input Capacitance	C <sub>ISS</sub>				2200			
Output Capacitance	Coss	V <sub>GS</sub> = 0 V, f = 1 MHz, V <sub>DS</sub> = 50 V			900		pF	
Reverse Transfer Capacitance	C <sub>RSS</sub>				17			
Total Gate Charge	Q <sub>G(TOT)</sub>	V <sub>GS</sub> = 4.5 V, V <sub>DS</sub> = 30 V; I <sub>D</sub> = 50 A			16			
Total Gate Charge	Q <sub>G(TOT)</sub>	V <sub>GS</sub> = 10 V, V <sub>DS</sub> = 30 V; I <sub>D</sub> = 50 A			34		1	
Threshold Gate Charge	Q <sub>G(TH)</sub>	V <sub>GS</sub> = 4.5 V, V <sub>DS</sub> = 30 V; I <sub>D</sub> = 50 A			1.5		nC	
Gate-to-Source Charge	Q <sub>GS</sub>				5.6			
Gate-to-Drain Charge	$Q_{GD}$				5.1			
Plateau Voltage	$V_{GP}$				2.8		V	
SWITCHING CHARACTERISTICS (Note:	5)							
Turn-On Delay Time	t <sub>d(ON)</sub>				10			
Rise Time	t <sub>r</sub>	V <sub>GS</sub> = 4.5 V, V	<sub>DS</sub> = 30 V,		15		ns	
Turn-Off Delay Time	t <sub>d(OFF)</sub>	$V_{GS} = 4.5 \text{ V}, \text{ V}_{D}$ $I_{D} = 50 \text{ A}, \text{ R}_{G}$	$= 2.5 \Omega$		24			
Fall Time	t <sub>f</sub>				5.0			
DRAIN-SOURCE DIODE CHARACTERIS	STICS							
Forward Diode Voltage	V <sub>SD</sub>	V <sub>GS</sub> = 0 V,	T <sub>J</sub> = 25°C		0.88	1.2		
	,	T <sub>J</sub> = 125°C		0.78		· V		
Reverse Recovery Time	t <sub>RR</sub>	$V_{GS} = 0 \text{ V, } dI_{S}/dt = 100 \text{ A/}\mu\text{s,}$ $I_{S} = 50 \text{ A}$			41		ns	
Charge Time	t <sub>a</sub>				21			
Discharge Time	t <sub>b</sub>				20			
Reverse Recovery Charge	$Q_RR$				32		nC	

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

4. Pulse Test: pulse width  $\leq 300~\mu s$ , duty cycle  $\leq 2\%$ .

5. Switching characteristics are independent of operating junction temperatures.

#### **TYPICAL CHARACTERISTICS**

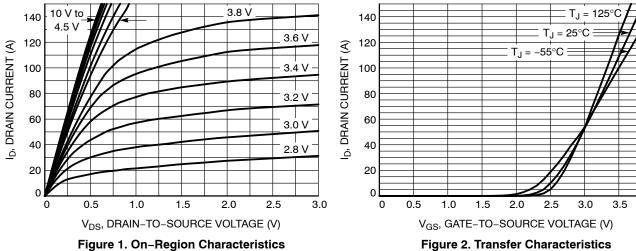


Figure 1. On-Region Characteristics

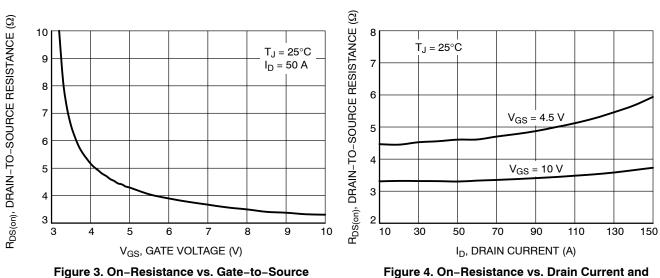


Figure 3. On-Resistance vs. Gate-to-Source Voltage

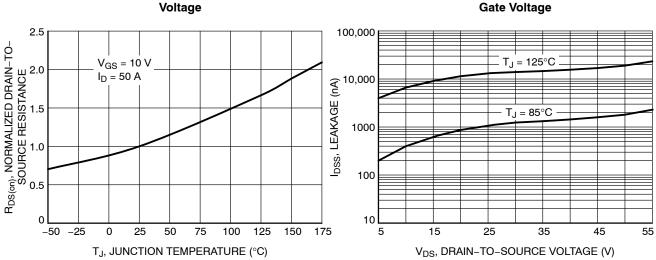
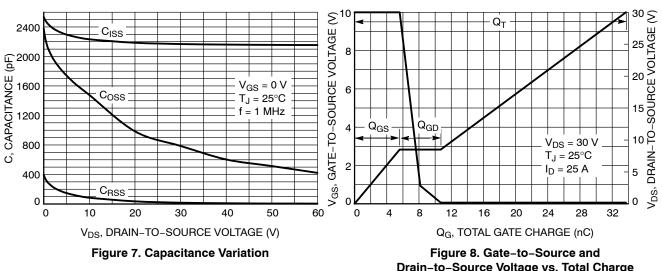


Figure 5. On-Resistance Variation with **Temperature** 

Figure 6. Drain-to-Source Leakage Current vs. Voltage

4.0

#### **TYPICAL CHARACTERISTICS**



Drain-to-Source Voltage vs. Total Charge

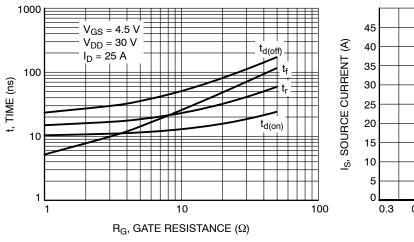


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

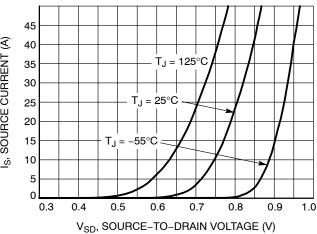


Figure 10. Diode Forward Voltage vs. Current

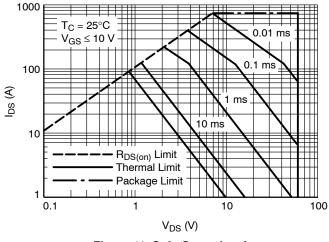


Figure 11. Safe Operating Area

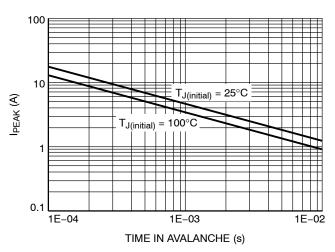


Figure 12. I<sub>PEAK</sub> vs. Time in Avalanche

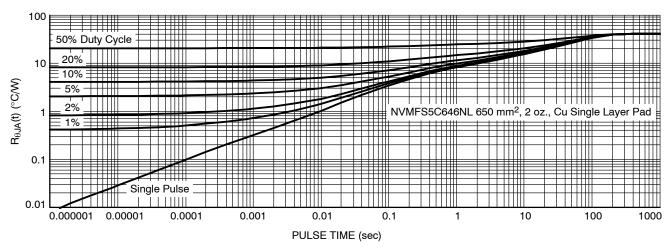


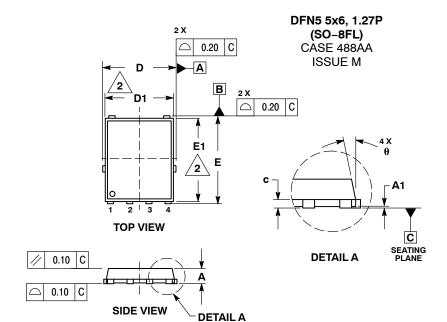
Figure 13. Thermal Characteristics

#### **DEVICE ORDERING INFORMATION**

Device	Marking	Package	Shipping <sup>†</sup>
NVMFS5C645NLT1G	5C645L	DFN5 (Pb-Free)	1500 / Tape & Reel
NVMFS5C645NLWFT1G	645LWF	DFN5 (Pb-Free, Wettable Flanks)	1500 / Tape & Reel
NVMFS5C645NLT3G	5C645L	DFN5 (Pb-Free)	5000 / Tape & Reel
NVMFS5C645NLWFT3G	645LWF	DFN5 (Pb-Free, Wettable Flanks)	5000 / Tape & Reel
NVMFS5C645NLAFT1G	5C645L	DFN5 (Pb-Free)	1500 / Tape & Reel
NVMFS5C645NLWFAFT1G	645LWF	DFN5 (Pb-Free, Wettable Flanks)	1500 / Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

#### PACKAGE DIMENSIONS



#### NOTES:

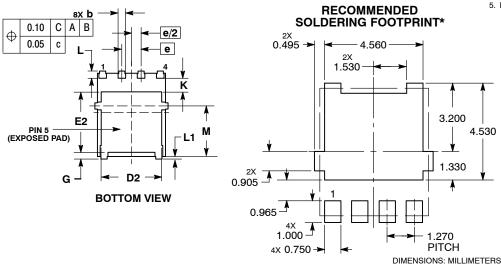
- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
- 2. CONTROLLING DIMENSION: MILLIMETER.
  3. DIMENSION D1 AND E1 DO NOT INCLUDE
- MOLD FLASH PROTRUSIONS OR GATE BURRS.

	MILLIMETERS			
DIM	MIN	NOM	MAX	
Α	0.90	1.00	1.10	
A1	0.00		0.05	
b	0.33	0.41	0.51	
С	0.23	0.28	0.33	
D	5.00	5.15	5.30	
D1	4.70	4.90	5.10	
D2	3.80	4.00	4.20	
E	6.00	6.15	6.30	
E1	5.70	5.90	6.10	
E2	3.45	3.65	3.85	
е	1.27 BSC			
G	0.51	0.575	0.71	
K	1.20	1.35	1.50	
L	0.51	0.575	0.71	
L1	0.125 REF			
М	3.00	3.40	3.80	
θ	0 °		12 °	

#### STYLE 1:

PIN 1. SOURCE

- SOURCE
- SOURCE GATE
- DRAIN



\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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